



Laboratoria De Nayer v.z.w.
Department of Electronics
Section E.M.C.

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Photo's test setup	
Product	DS RFID
LDN Number	LDN3918
Date of issue	2019-02-11
Standard	FCC part 15 subpart C
EMC report	PCC-RAD-4885

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Laboratoria De Nayer v.z.w.

The results refer to the described sample or equipment under test only.

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In case the customer wants to refer to his appeal to our accredited laboratories, he will use the following orequivalent sentence: "Tested by Laboratoria De Nayer, E.M.C.department, accredited by BELAC for EMC-immunity and EMC-emission under registration number 041-T".

photo : conducted emission set-up (0.15-30MHz)

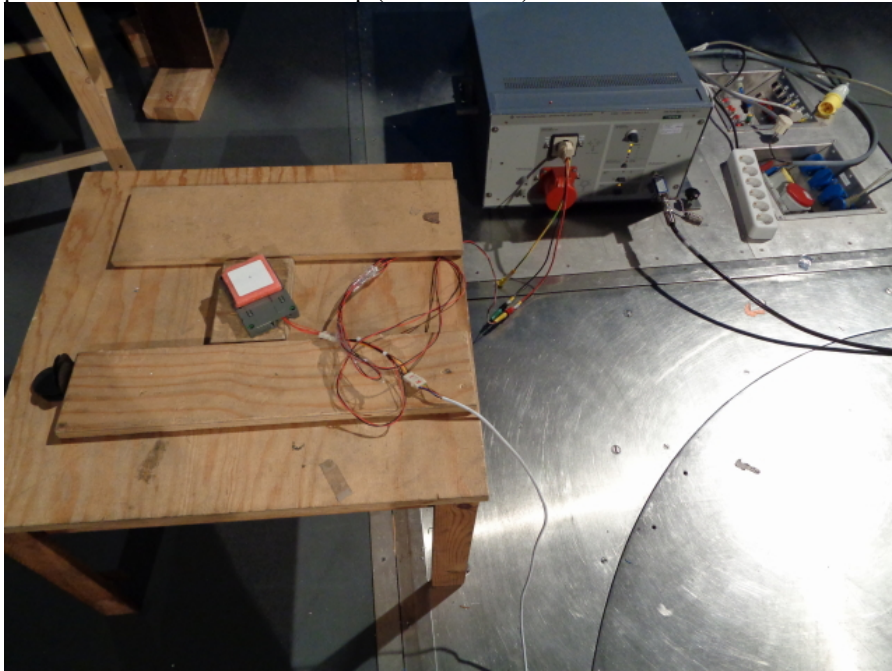


photo 2: radiated emission set-up (9k-30MHz)

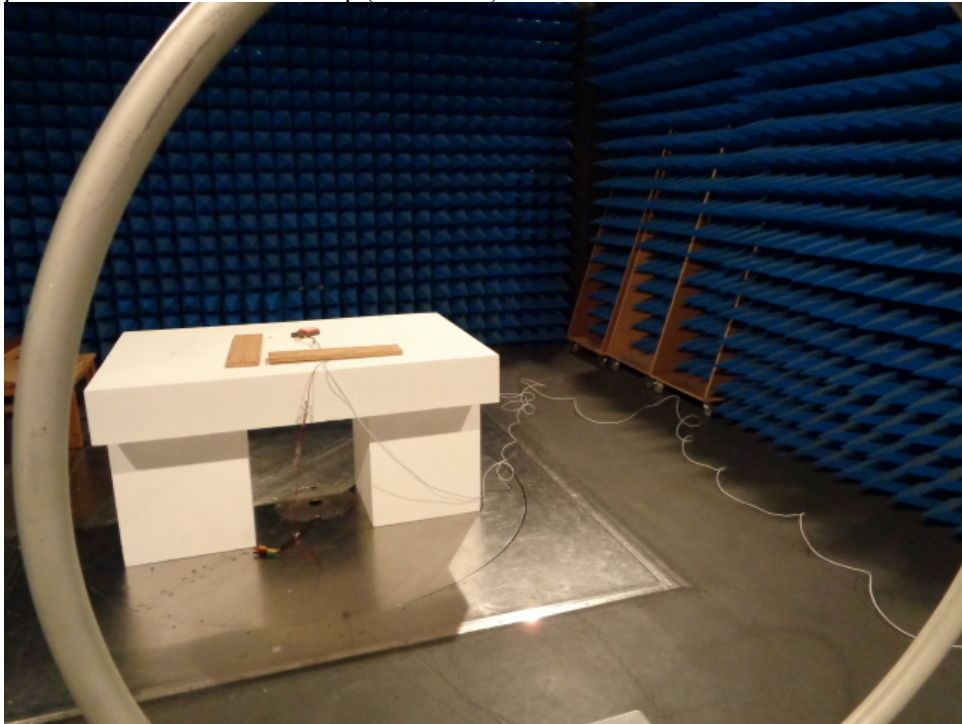


Photo : radiates emission (30-200MHz)

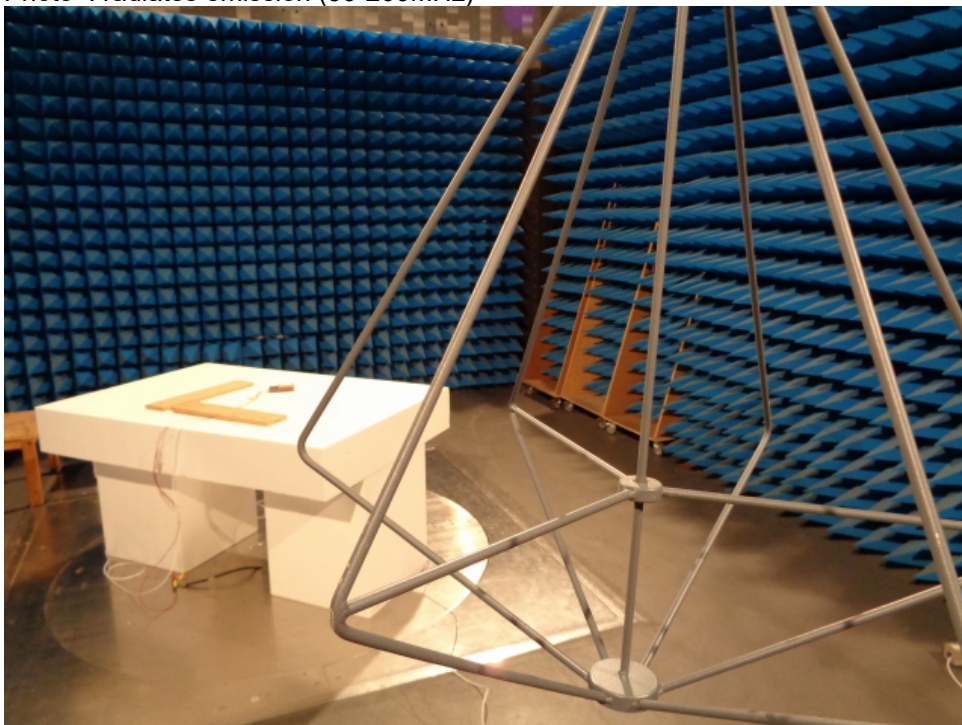


Photo : radiates emission (200-1000MHz)



Photo : EUT in thermal chamber

